

Class	Subclass	ISSUE CLASSIFICATION

N P

PATENT NO.

U.S. UTILITY Patent Application

O.I.P.E.	PATENT DATE
SCANNED 02 00 00	

APPLICATION NO. 09/976579	CONT/PRIOR D	CLASS 250	SUBCLASS 559.27	ART UNIT 2878	EXAMINER S. SONG
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APPLICANTS Sundar Amartur 2877 GEISEL

TITLE In-situ detection of thin-metal interface using high resolution spectral analysis of optical interference

PTO-2040
12/99

ISSUING CLASSIFICATION

EXAMINER NOTICE OF ALLOWANCE MAILED ISSUE FEE Amount Due Date Paid ISSUE BATCH NUMBER	DRAWINGS		
	Sheets Drawg.	Figs. Drawg.	Print Fig.
	The term of this patent subsequent to (date) has been disclaimed. (Assistant Examiner) (Date)		
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